


<b>Search Notes</b>  	<b>Application/Control No.</b>  10584717	<b>Applicant(s)/Patent Under Reexamination</b>  YOON ET AL.
	<b>Examiner</b>  PHUOC DOAN	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
See Attached Search History	6/15/2010	PHD

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--